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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10027639	FILING DATE 12/19/2001	CLASS 382	SUBCLASS 462.250	GAU 3624	EXAMINER SANDEKS, A.
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Jeong-Ho;

255

2876

**CONTINUING DATA VERIFIED:

None

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** FOREIGN APPLICATIONS VERIFIED:
REPUBLIC OF KOREA 2001-2569 01/17/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	9903-44
Verified and Acknowledged Examiners's initials <i>u</i>		
TITLE : Method and apparatus for detecting defective markings on a semiconductor product		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs. Drwg.
Amount Due	Date Paid	Print Fig.	
Primary Examiner		Applicati n Examiner	
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